Se	earch	rch Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/615,600	ONOE ET AL.	
Examiner	Art Unit	
Joseph Haley	2627	

SEARCHED			
Class	Subclass	Date	Examiner
			*
			:
		*	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
			-
	I interference irch	5/14/2007	jrh

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
see attached EAST search notes	5/9/2007	JRH
consulted Viet Nguyen about independent claims 3, 7, 16 and 20	5/14/2007	JRH